

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
		Examiner Linh T. Nguyen	Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0017833	08-2001	Yamada et al.	369/59.11
*	B	US-2003/0081523	05-2003	Miyagawa et al.	369/59.11
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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